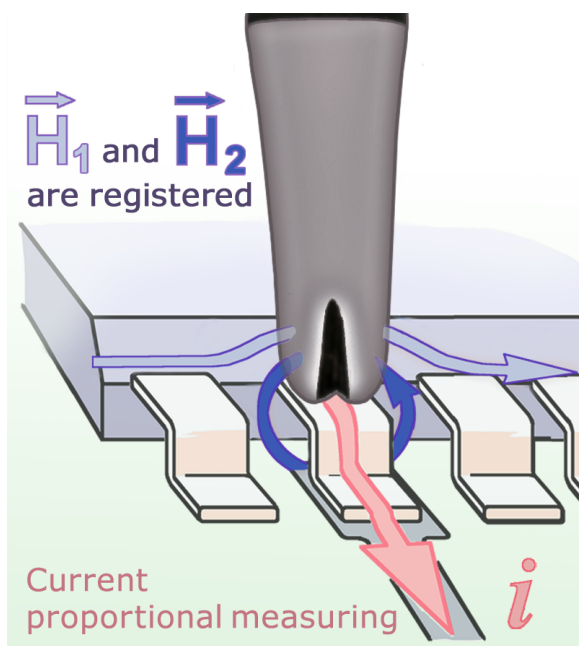


XF-U 2.5-1

H-Field Probe 30 MHz up to 6 GHz

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Short description

The XF-U 2.5-2 near-field probe is designed for the selective measurements of RF currents in conducting paths, component connectors, SMD components, and IC pins. The probe head has a magnetically active gap with an approx. width of 0.5 mm. To use, the head should be positioned directly onto the measured object.

The XF-U 2.5-2 is a passive near-field probe that is designed for SMD components (pins). The near-field probe is small and handy. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe has an internal terminating resistance.

Technical parameters

Frequency range	30 MHz ... 6 GHz
Resolution	≈ 0.5 mm
Probe head dimensions	$\varnothing \approx 4$ mm
Connector - output	SMA, female, jack
Weight	15 g

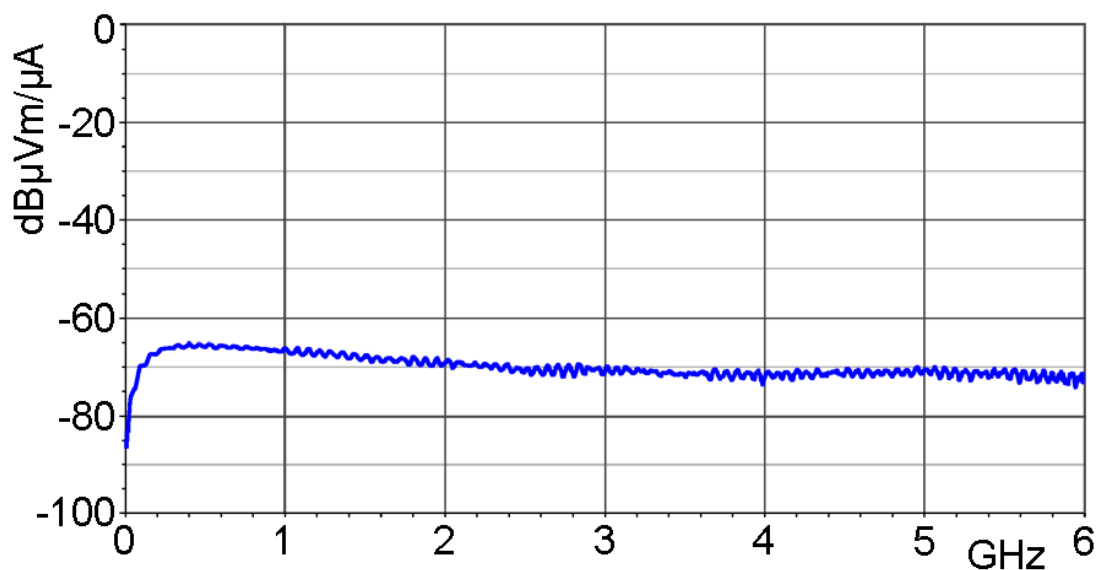


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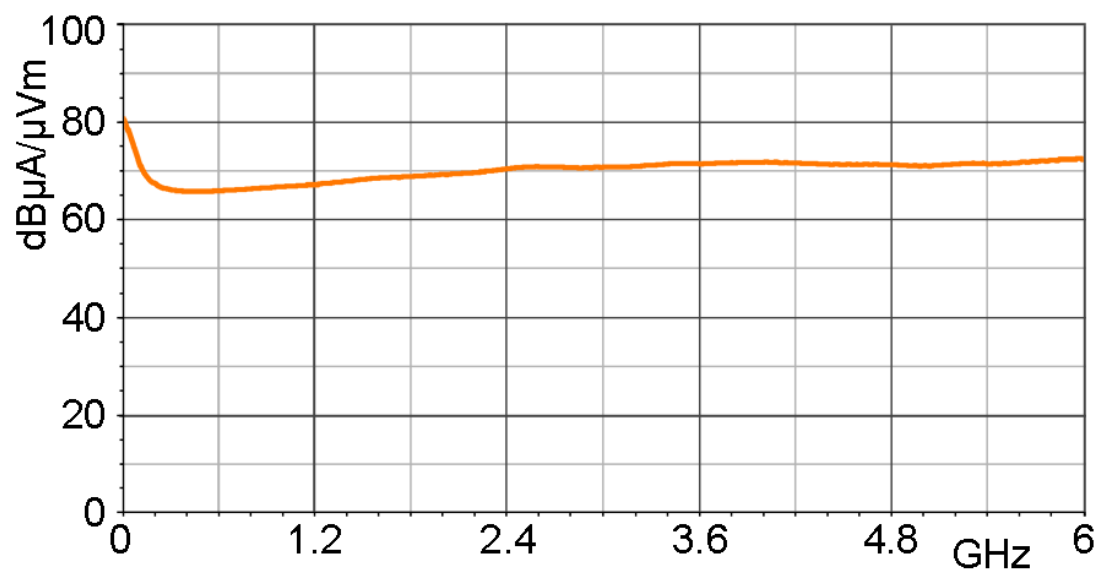
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Frequency response [dB μ V] / [dB μ A/m]



H-field correction curve [dB μ A/m] / [dB μ V]

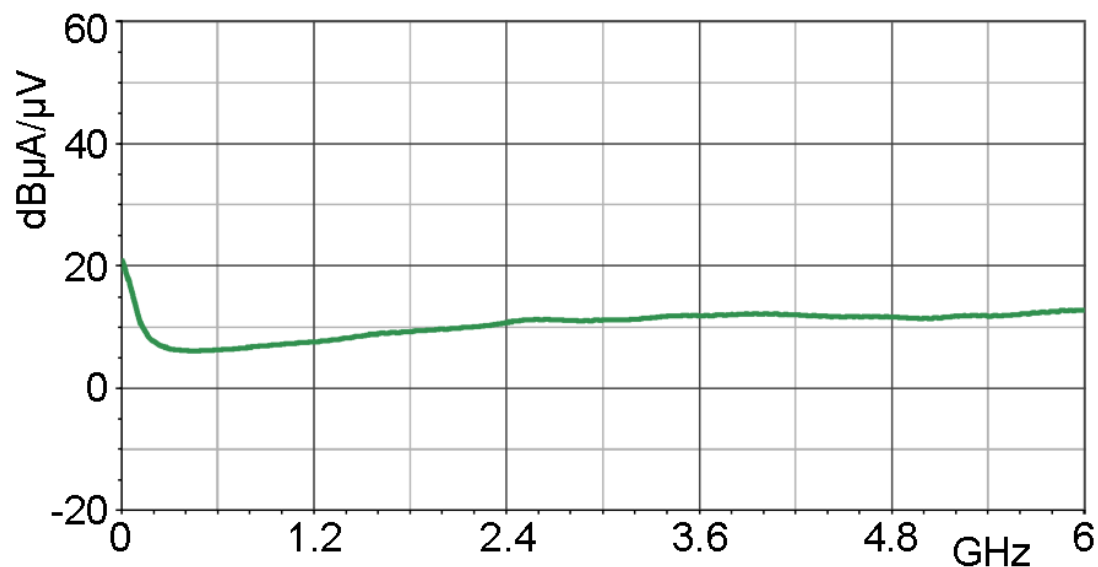


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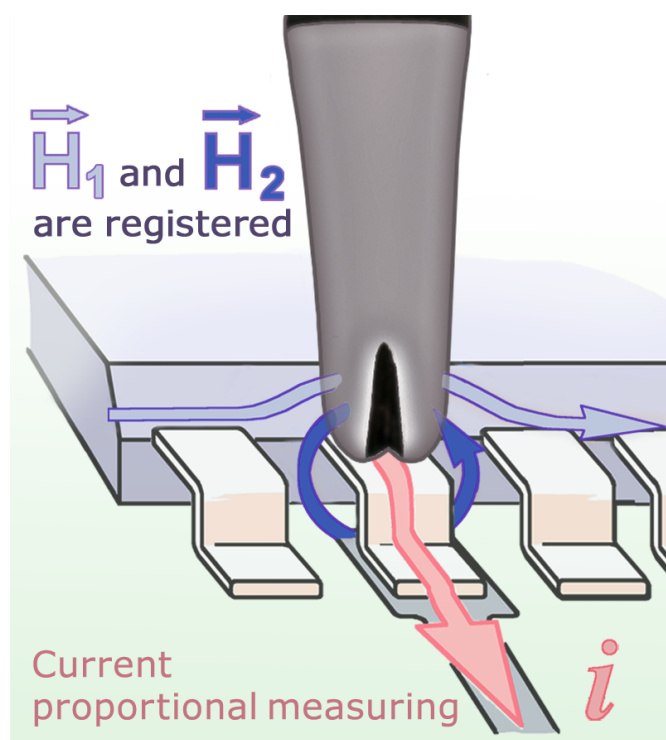
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Current correction curve [dB μ A] / [dB μ V]



Measuring principles



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Probe head

